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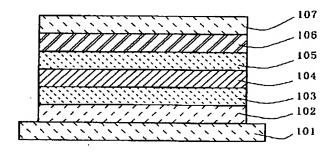
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# (54) 【発明の名称】 スピンパルブ効果センサ

# (57)【要約】

【課題】反強磁性CrMnPt膜と隣接する強磁性膜の結晶系を同じにすることにより、大きな交換結合磁界が得られるスピンバルブ効果センサを提供する。

【解決手段】強磁性膜に反強磁性膜を隣接させてその膜間の交換結合によって前記強磁性膜の磁化方向を固定しているスピンバルブ効果センサにおいて、前記反強磁性膜がbcc結晶構造のCrMnPt膜であり、前記強磁性膜がbcc結晶構造をしているものである。



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#### 【特許請求の範囲】

【請求項1】 強磁性膜に反強磁性膜を隣接させてその 膜間の交換結合によって前記強磁性膜の磁化方向を固定 しているスピンバルブ効果センサにおいて、

前記反強磁性膜がbcc結晶構造のCrMnPt膜であり、前記強磁性膜がbcc結晶構造をしていることを特 徴とするスピンバルブ効果センサ。

【請求項2】 前記反強磁性膜が C r 30-70 M n 30-70 P t 3-30 (原子%) で示される組成を有することを特徴とする請求項1 記載のスピンバルブ効果センサ。

【請求項3】 前記強磁性膜がFeNiCo膜であることを特徴とする請求項1あるいは2に記載のスピンバルブ効果センサ。

【請求項4】 前記FeNiCo膜がFe<sub>20-100</sub>Ni 0-38Co<sub>80-0</sub> (原子%) で示される組成を有することを 特徴とする請求項3に記載のスピンバルブ効果センサ。 【発明の詳細な説明】

#### [0001]

【発明の属する技術分野】本発明は磁気ディスク装置に 用いられるスピンバルブ効果センサに関する。

#### [0002]

【従来の技術】磁気的に記録されたデータを検出するため異方性磁気抵抗効果を用いた磁気抵抗センサを使用することはよく知られている。最近では、磁気抵抗センサの抵抗変化が、非磁性層を介する磁性層間での伝導電子のスピン依存性伝送、および、それに付随する層界面でのスピン依存性散乱に帰される、より顕著な磁気抵抗効果の利用が研究されている。この磁気抵抗効果は、「巨大磁気抵抗効果」や「スピンバルブ効果」などの名称で呼ばれている。このような磁気抵抗センサは異方性磁気30抵抗効果を利用する磁気抵抗センサで観察されるよりも感度が改善されて抵抗変化が大きい。

【0003】スピンバルブ効果センサは、非磁性膜によって分離された第一の強磁性膜および第二の強磁性膜を含む積層構造が適切な物質上に形成されている。強磁性膜の一つ、例えば第二の強磁性膜の磁化方向は、外部印加磁界ゼロで、第一の強磁性膜の磁化方向と垂直に固定されている。第二の強磁性膜の磁化方向の固定は、反強磁性膜を隣接させ、反強磁性膜と第二の強磁性膜との交換結合によって行われる。そこで第二の強磁性膜は「固40定層」と呼ばれることがある。その代表的な磁化の固定方向は浮上面と垂直方向である。一方、第一の強磁性膜の磁化方向は外部印加磁界に応じて自由に回転でき、

「自由層」と呼ばれることがある。外部印加磁界に応じて自由層の磁化方向が自由に回転し、必然的に固定層の磁化方向と自由層の磁化方向との間の角度が変化する。 スピンバルブ効果センサは、これら磁化方向の角度変化に応じて電気抵抗が変化することを利用し、媒体からの磁気的信号を電気的信号に変換する磁気抵抗センサである。

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【0004】バイアス磁界印加手段としての反強磁性膜には強磁性膜と反強磁性膜との間の交換結合磁界が大きいこと、さらに交換結合磁界が消失する温度で定義される「ブロッキング温度」が高いことが要求される。欧州特許EP490608A2号では、これらを満足する反強磁性膜はFeMn,NiMn系反強磁性膜であることが開示されている。これらの反強磁性膜と強磁性NiFe膜との間に大きな交換結合磁界、ブロッキング温度を示す。しかし、耐蝕性が著しく低く応用上困難な点が多10い。

【0005】そこで、耐触性の高い反強磁性膜としてC r 30-70 M n 30-70 P t 3-30 (原子%) が特開平9-1 6 9 2 3 号などに提案されている。このC r M n P t E は C r 含有量が多いために耐触性が改善されており、腐 触電流密度を測定すると、反強磁性C r M r E t

【0006】この反強磁性CrMnPt膜は、bcc結晶構造を有しているにもかかわらず、fcc結晶構造を有している強磁性NiFe膜にエピタキシャル成長しており、このエピタキシャル成長するときに大きな交換結合磁界が得られる、と特開平9-16923号は述べている。

#### [0007]

【発明が解決しようとする課題】しかし、bcc結晶構造を有している反強磁性膜をfcc結晶構造の強磁性膜の上にエピタキシャル成長させることは非常に難しく、スパッタリングの条件によっては、隣接する結晶格子に歪みが生じて、交換結合磁界が小さくなることがあった。

【0008】そこで、本発明では、反強磁性CrMnP t膜と隣接する強磁性膜の結晶系を同じにすることによ り、大きな交換結合磁界が得られるスピンバルブ効果セ ンサを提供することを目的としている。

## [0009]

【課題を解決するための手段】本発明のスピンバルブ効果センサは、強磁性膜に反強磁性膜を隣接させてその膜間の交換結合によって前記強磁性膜の磁化方向を固定しているものにおいて、前記反強磁性膜がbcc結晶構造のCrMnPt膜であり、前記強磁性膜がbcc結晶構造をしていることを特徴とするものである。

【0010】また、前記反強磁性膜がCr30-70 Mn30-70 Pt3-30 (原子%)で示される組成を有することが好ましい。反強磁性CrMnPt膜の組成範囲は常温においてbcc結晶構造を有するとともに、反強磁性を示すものとして定めてある。ここで、Ptに代えてあるいはその一部をCu, Au, Co, Niあるいは白金族の内から選択された一種以上の金属元素で置換したものも同様の効果が得られる。

【0011】また前記強磁性膜がFeNiCo膜である

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ことが好ましく、更に好ましくは $Fe_{20-100}Ni_{0-38}Co_{80-0}$  (原子%) で示される組成である。強磁性 $FeN_{i}Co$ 膜の組成範囲は常温においてbcc 結晶構造を有するものとして定めてある。

【0012】スピンバルブ効果センサは、Cu等からなる非磁性膜によって分離されて、その非磁性膜の両側面に強磁性膜が形成されていて、これら2つの強磁性膜の一方が反強磁性膜と積層されて固定層となっており、2つの強磁性膜の他方が自由層となっている。本発明において、固定層となっている強磁性膜全体をbcc結晶構10造とすることもできるが、固定層を2層以上の積層構造として、Cu等からなる非磁性膜と隣接している側を例えばCoを主成分としたfcc結晶構造を持った膜として、bcc結晶構造を持った反強磁性CrMnPt膜と隣接している部分の強磁性膜をbcc結晶構造とすることもできる。

# [0013]

【発明の実施の形態】図1に、本発明のスピンバルブ効 果センサの浮上面から見た拡大断面図を示す。ここで、 Al<sub>2</sub>O<sub>3</sub> あるいはAl<sub>2</sub>O<sub>3</sub>-TiCなどからなる基 20 板101の上に、非磁性下地膜102、強磁性膜からな る自由層103、Cuなどからなる非磁性中間膜10 4、強磁性膜からなる固定層105、反強磁性膜10 6、非磁性保護膜107を順次積層した層で構成されて いる。非磁性下地膜102は2~10mm厚のTa膜、 強磁性膜からなる自由層103は3~10nm厚のFe NiCo膜でbcc結晶構造をしている。非磁性中間膜 104は1.5~5nm厚のCuより構成されておりf c c 結晶構造をしている。強磁性膜からなる固定層 1 0 5は1.5~5nm厚のFeNiCo膜でbcc結晶構30 造をしている。反強磁性膜106は5~20mm厚のC rMnPt膜でbcc結晶構造をしている。非磁性保護 膜107はTaである。

【0014】これらの膜はスパッタリング法により室温で真空中で連続的に形成した。固定層105のFeNiCo膜をスパッタリングする際に膜に一方向の磁界を印加して、固定層105のFeNiCo膜の上に、反強磁性膜106のCrMnPtをスパッタリングすることによって、bcc結晶構造をしたFeNiCo膜の上40に、bcc結晶構造をしたFeNiCo膜の上40に、bcc結晶構造をしたCrMnPt膜がエピタキシャル成長し、この反強磁性膜106の磁気モーメントが揃えられた。これによって、反強磁性膜106と強磁性膜105との間で交換結合磁界が発生し、強磁性膜105に一方向異方性を付与することができた。

【0015】比較のために、上記の強磁性FeNiCo 膜からなる固定層105に代えて、fcc結晶構造をし た強磁性NiFe膜を用いた以外は、上記と同様に作製 した比較例のスピンバルブ効果センサを用意した。この 比較例のスピンバルブ効果センサと、図1に示す本発明50 4

のスピンバルブ効果センサについて、交換結合磁界の強さを強磁性膜固定層の厚み (nm) に対する関係で、比較して示したグラフが図2である。図2で縦軸の交換結合磁界 (Hex) は任意単位で示しているが、fcc結晶構造をした強磁性膜固定層を用いた比較例のものに比して、bcc結晶構造をした強磁性膜固定層を用いている本発明のスピンバルブ効果センサは極めて大きな交換結合磁界を示す。別の測定では、bcc結晶構造の反強磁性CrMnPt膜とfcc結晶構造をした3nm厚の強磁性CompFe10 (原子%) 膜との間の交換結合磁界は約3000eであるのに対して、同じ反強磁性膜とbcc結晶構造をした3nm厚の強磁性Fe80Ni10Co10 (原子%) 膜の交換結合磁界は約4000eであった。

【0016】図3に、本発明のスピンバルブ効果センサ の他の実施例について、浮上面から見た拡大断面図を示 している。図3で図1と同じ部分については同じ符号を 用いて示している。ここで強磁性膜自由層110は2層 構造をしており、非磁性下地膜102に隣接する層はf cc結晶構造のNiFe膜111であり、非磁性中間膜 104と隣接する層はfcc結晶構造のCoFe膜11 2である。また強磁性膜固定層120も2層構造をして おり、非磁性中間膜104と隣接する層はfcc結晶構 造のCoFe膜121であり、反強磁性膜106と隣接 する層はbcc結晶構造のFeNiCo膜122であ る。この構造を持ったスピンバルブ効果センサは、Cu などの非磁性中間膜104を挟んでいる強磁性膜をCo 合金としているので電子散乱効果が大で、磁気抵抗効果 が大きい。しかも、反強磁性膜106と隣接している強 磁性FeNiCo膜122がbcc結晶構造をしている ので、これらの膜の間でエピタキシャル成長が起こして いるので交換結合磁界が大きい。

#### [0017]

【発明の効果】本発明のスピンバルブ効果センサは反強磁性膜として耐蝕性に優れたCrMnPt膜を有しているとともに、この反強磁性膜に隣接する強磁性膜の結晶系をCrMnPt膜と同じbcc結晶構造としたことによって、大きな交換結合磁界が得られる。

#### 【図面の簡単な説明】

【図1】本発明のスピンバルブ効果センサの浮上面から 見た拡大断面図である。

【図2】スピンバルブ効果センサの交換結合磁界の強さ と強磁性膜固定層の関係を示す図である。

【図3】本発明のスピンバルブ効果センサの他の実施例 の浮上面から見た拡大断面図である。

強磁性膜(自由層)

#### 【符号の説明】

103, 110

101 基板

102 非磁性下地膜

104 非磁性中間膜

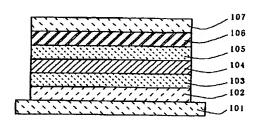
105、120強磁性膜(固定層)106反強磁性膜107非磁性保護膜

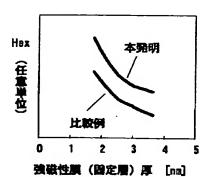
 1 1 1
 NiFe膜

 1 1 2、1 2 1
 CoFe膜

 1 2 2
 FeNiCo膜

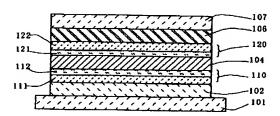
【図1】





【図2】

【図3】



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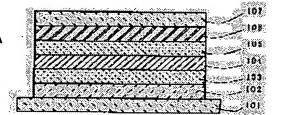
HAGIWARA HIDETOSHI

# (54) SPIN VALVE EFFECT SENSOR

(57) Abstract:

PROBLEM TO BE SOLVED: To obtain a sensor achieving a large exchange linking magnetic field, by forming an antiferromagnetic film of a CrMnPt film of a bcc crystal structure and a ferromagnetic film of the bcc crystal structure, preferably forming the ferromagnetic film of an FeNiCo film, and specifying compositions of the films.

SOLUTION: A non-magnetic undercoat film 102 is a Ta film having a thickness of 2-10 nm and a free layer 103 of a ferromagnetic film is an FeNiCo film having a thickness of 3-10 nm in a bcc crystal structure. A non-magnetic intermediate film 104 is constituted of 1.5 to 5 nm-thick Cu in an fcc crystal structure, and a film layer 105 of a ferromagnetic film is an FeNiCo film having a thickness of 1.5-5 nm in the bcc crystal structure. An antiferromagnetic film 106 is a Cr30-70Mn30-70Pt3-30 (at.%) film having a thickness of 5-20 nm in the bcc crystal structure. A non-magnetic protecting film 107 is formed of Ta. In sputtering the Fe20-100Ni0-38Co80-0 (at.%) film of the fixed layer 105, a magnetic field in a constant direction is applied to the film.



# **EGAL STATUS**

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# **DETAILED DESCRIPTION**

[Detailed Description of the Invention]

[The technical field to which invention belongs] this invention relates to the spin bulb effect sensor used for a magnetic disk unit.

[0002]

[Description of the Prior Art] In order to detect the data recorded magnetically, using the magnetic-reluctance sensor using the anisotropy magnetoresistance effect is known well. Recently, the use of the more remarkable magnetoresistance effect returned to spin dependency dispersion by the layer interface to which resistance change of a magnetic-reluctance sensor accompanies spin dependency transmission of the conduction electron between the magnetic layers through a non-magnetic layer and it is studied. This magnetoresistance effect is called under the name of the "huge magnetoresistance effect", the "spin bulb effect", etc. Sensitivity is improved and such a magnetic-reluctance sensor has a large resistance change rather than it is observed by the magnetic-reluctance sensor using the anisotropy magnetoresistance effect.

[0003] The spin bulb effect sensor is formed on the matter with the suitable laminated structure containing the first ferromagnetic separated by the nonmagnetic membrane, and the second ferromagnetic. One of the ferromagnetics, for example, the magnetization direction of the second ferromagnetic, is external impression magnetic field zero, and it is being fixed to the first magnetization direction and perpendicular of a ferromagnetic. Fixation of the magnetization direction of the second ferromagnetic makes an antiferromagnetism film adjoin, and is performed by the switched connection of an antiferromagnetism film and the second ferromagnetic. Then, the second ferromagnetic may be called "fixed bed." The fixed direction of the typical magnetization is as perpendicular as a surfacing side. On the other hand, according to an external impression magnetic field, it can rotate freely, and the magnetization direction of the first ferromagnetic may be called "free layer." According to an external impression magnetic field, the magnetization direction of a free layer rotates freely, and the angle between the magnetization direction of the fixed bed and the magnetization direction of a free layer changes inevitably. The spin bulb effect sensor is a magnetic-reluctance sensor which uses that electric resistance changes according to angle change of these magnetization direction, and changes the magnetic signal from a medium into an electric signal. [0004] It is required for the antiferromagnetism film as a bias magnetic field impression means that the switched connection magnetic field between a ferromagnetic and an antiferromagnetism film is large and that the "blocking temperature" from which it defines as the temperature to which a switched connection magnetic field disappears further should be high. It is indicated that the antiferromagnetism films which are satisfied [ with the Europe patent EP 490608ANo. 2 ] of these are FeMn and a NiMn system antiferromagnetism film. A big switched connection magnetic field and blocking temperature are shown between these antiferromagnetism films and a ferromagnetic NiFe film. However, there are many points that it is remarkable, and is low and an application top is difficult for corrosion resistance.

[0005] Then, Cr30-70 Mn30-70 Pt 3-30 (atomic %) is proposed by JP,9-16923,A etc. as a corrosion-resistant high antiferromagnetism film. since this CrMnPt film has many Cr contents, if corrosion resistance is improved and corrosion current density is measured — an antiferromagnetism CrMnPt film — 10-4 A/m2 it is — 10-2 A/m2 of an antiferromagnetism NiMn film It compares and excels extremely.

[0006] This antiferromagnetism CrMnPt film is growing epitaxially on the ferromagnetic NiFe film which has the fcc crystal structure in spite of having the bcc crystal structure, and JP,9-16923,A says that a big switched connection magnetic field is acquired when [ this ] growing epitaxially.

[0007]

[Problem(s) to be Solved by the Invention] However, depending on the conditions of sputtering, it was very difficult to grow epitaxially the antiferromagnetism film which has the bcc crystal structure on the ferromagnetic of the fcc crystal structure, and distortion arose in the adjoining crystal lattice, a switched connection magnetic field is small and it had a bird clapper.

[0008] Then, in this invention, it aims at offering the spin bulb effect sensor by which a big switched connection magnetic field is acquired by making the same crystal system of the ferromagnetic which adjoins an antiferromagnetism CrMnPt film.

[0009]

[Means for Solving the Problem] In what an antiferromagnetism film is made to adjoin a ferromagnetic and is fixing the magnetization direction of the aforementioned ferromagnetic by the switched connection between the film, the aforementioned antiferromagnetism film is a CrMnPt film of the bcc crystal structure, and the spin bulb effect sensor of this invention is characterized by the aforementioned ferromagnetic carrying out the bcc crystal structure. [0010] Moreover, it is desirable to have the composition the aforementioned antiferromagnetism film is indicated to be by Cr30-70 Mn30-70 Pt 3-30 (atomic %). The composition range of an antiferromagnetism CrMnPt film is defined as what shows antiferromagnetism while it has the bcc crystal structure in ordinary temperature. Here, it replaces with Pt or an effect with the same said of what replaced the part by the metallic element more than a kind chosen from from among Cu, Au, Co, nickel, or the platinum group is acquired.

[0011] Moreover, it is the composition it is indicated to be desirable still more preferably by Fe20-100nickel0-38Co 80-0 (atomic %) that the aforementioned ferromagnetic is a FeNiCo film. The composition range of a ferromagnetic

FeNiCo film is defined as what has the bcc crystal structure in ordinary temperature.

[0012] The spin bulb effect sensor is separated by the nonmagnetic membrane which consists of Cu etc., the ferromagnetic is formed in the both-sides side of the nonmagnetic membrane, the laminating of one side of these two ferromagnetics is carried out to an antiferromagnetism film, it serves as the fixed bed, and another side of two ferromagnetics serves as a free layer. Although the whole ferromagnetic used as the fixed bed can also be made into the bcc crystal structure in this invention, the ferromagnetic of the portion which adjoins the antiferromagnetism CrMnPt film with the bcc crystal structure as a film with the fcc crystal structure which made Co the principal component for the side [ it adjoins the nonmagnetic membrane which consists of Cu etc. considering the fixed bed as a laminated structure more than two-layer ] can also be made into the bcc crystal structure.

[0013]

[Embodiments of the Invention] The expanded sectional view seen from the surfacing side of the spin bulb effect sensor of this invention to <u>drawing 1</u> is shown. Here, it is aluminum 203. Or it consists of layers which carried out the laminating of the nonmagnetic interlayer 104 which consists of a free layer 103 which consists of a nonmagnetic ground film 102 and a ferromagnetic on the substrate 101 which consists of aluminum 203-TiC etc., Cu, etc., the fixed bed 105 which consists of a ferromagnetic, the antiferromagnetism film 106, and the nonmagnetic protective coat 107 one by one. The free layer 103 which the nonmagnetic ground film 102 becomes from Ta film of 2-10nm \*\* and a ferromagnetic is carrying out the bcc crystal structure by the FeNiCo film of 3-10nm \*\*. The nonmagnetic interlayer 104 consists of Cu(s) of 1.5-5nm \*\*, and is carrying out the fcc crystal structure. The fixed bed 105 which consists of a ferromagnetic is carrying out the bcc crystal structure by the FeNiCo film of 1.5-5nm \*\*. The antiferromagnetism film 106 is carrying out the bcc crystal structure by the CrMnPt film of 5-20nm \*\*. The

nonmagnetic protective coat 107 is Ta.

[0014] These films were continuously formed in the vacuum at the room temperature by the sputtering method. When carrying out sputtering of the FeNiCo film of the fixed bed 105, on the other hand, Mukai's magnetic field was impressed to the film, and the magnetic moment of the fixed bed 105 was turned in the direction of an impression magnetic field. On the FeNiCo film of the fixed bed 105, by carrying out sputtering of the CrMnPt of the antiferromagnetism film 106, the CrMnPt film which carried out the bcc crystal structure grew epitaxially, and the magnetic moment of this antiferromagnetism film 106 was arranged on the FeNiCo film which carried out the bcc crystal structure. By this, the switched connection magnetic field occurred between the antiferromagnetism film 106 and the ferromagnetic 105, and the 1 direction anisotropy was able to be given to the ferromagnetic 105. [0015] It replaced with the fixed bed 105 which consists of the above-mentioned ferromagnetic FeNiCo film for comparison, and the spin bulb effect sensor of the example of comparison produced like the above was prepared except having used the ferromagnetic NiFe film which carried out the fcc crystal structure, the graph which is a relation to the thickness (nm) which is the ferromagnetic fixed bed, and compared and showed switched connection magnetic field strength about the spin bulb effect sensor of this example of comparison and the spin bulb effect sensor of this invention shown in drawing 1 is drawing 2 Although the arbitrary unit shows the switched connection magnetic field (Hex) of a vertical axis by drawing 2, as compared with the thing of the example of comparison using the ferromagnetic fixed bed which carried out the fcc crystal structure, the spin bulb effect sensor of this invention which uses the ferromagnetic fixed bed which carried out the bcc crystal structure shows a very big switched connection magnetic field. The switched connection magnetic fields of ferromagnetic Fe80nickel10Co10 (atomic %) film of 3nm \*\* which considered the bcc crystal structure as the same antiferromagnetism film in another measurement to the switched connection magnetic fields between ferromagnetic Co90Fe10 (atomic %) films of 3nm \*\* which considered the fcc crystal structure as the antiferromagnetism CrMnPt film of the bcc crystal structure being about 300 Oe(s) were about 400 Oe(s).

[0016] The expanded sectional view seen from the surfacing side is shown in <u>drawing 3</u> about other examples of the spin bulb effect sensor of this invention. The portion same at <u>drawing 3</u> as <u>drawing 1</u> is shown using the same sign. The ferromagnetic free layer 110 is carrying out two-layer structure, the layer which adjoins the nonmagnetic ground film 102 is the NiFe film 111 of the fcc crystal structure, and the layer which adjoins the nonmagnetic interlayer 104 is the CoFe film 112 of the fcc crystal structure here. Moreover, the ferromagnetic fixed bed 120 is also carrying out two-layer structure, the layer which adjoins the nonmagnetic interlayer 104 is the CoFe film 121 of the fcc crystal structure, and the layer which adjoins the antiferromagnetism film 106 is the FeNiCo film 122 of the bcc crystal structure. Since the ferromagnetic which has sandwiched the nonmagnetic interlayers 104, such as Cu, is used as Co alloy, an electronic scattering effect is size, and the spin bulb effect sensor with this structure has the large magnetoresistance effect. And since the ferromagnetic FeNiCo film 122 contiguous to the antiferromagnetism film 106 is carrying out the bcc crystal structure and epitaxial growth has started among these films, a switched

connection magnetic field is large.

[0017]

[Effect of the Invention] While the spin bulb effect sensor of this invention has the CrMnPt film which was excellent in corrosion resistance as an antiferromagnetism film, a big switched connection magnetic field is acquired by having made into the same bcc crystal structure as a CrMnPt film crystal system of the ferromagnetic which adjoins this antiferromagnetism film.

[Translation done.]

#### \* NOTICES \*

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# **DESCRIPTION OF DRAWINGS**

[Brief Description of the Drawings]

Drawing 1 It is the expanded sectional view seen from the surfacing side of the spin bulb effect sensor of this invention.

[Drawing 2] It is drawing showing the switched connection magnetic field strength of the spin bulb effect sensor, and the relation of the ferromagnetic fixed bed.

[Drawing 3] It is the expanded sectional view seen from the surfacing side of other examples of the spin bulb effect sensor of this invention.

[Description of Notations]

101 Substrate

102 Nonmagnetic Ground Film

103 110 Ferromagnetic (free layer)

104 Nonmagnetic Interlayer

105 120 Ferromagnetic (fixed bed)

106 Antiferromagnetism Film

107 Nonmagnetic Protective Coat

111 NiFe Film

112 121 CoFe film

122 FeNiCo Film

[Translation done.]

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#### **CLAIMS**

[Claim(s)]

[Claim 1] The spin bulb effect sensor which the aforementioned antiferromagnetism film is a CrMnPt film of the bcc crystal structure, and is characterized by the aforementioned ferromagnetic carrying out the bcc crystal structure in the spin bulb effect sensor which an antiferromagnetism film is made to adjoin a ferromagnetic and is fixing the magnetization direction of the aforementioned ferromagnetic by the switched connection between the film.
[Claim 2] The spin bulb effect sensor according to claim 1 characterized by having the composition the aforementioned antiferromagnetism film is indicated to be by Cr30–70 Mn30–70 Pt 3–30 (atomic %).
[Claim 3] The claim 1 characterized by the aforementioned ferromagnetic being a FeNiCo film, or the spin bulb effect sensor given in 2.

[Claim 4] The spin bulb effect sensor according to claim 3 characterized by having the composition the aforementioned FeNiCo film is indicated to be by Fe20-100nickel0-38Co 80-0 (atomic %).

[Translation done.]